

April 1988 Revised September 2000

74F37

Quad Two-Input NAND Buffer

General Description

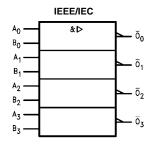
This device contains four independent gates, each of which performs the logic NAND function.

Ordering Code:

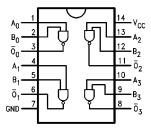
Order Number	Package Number	Package Description
74F37SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow
74F37SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F37PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L. HIGH/LOW	Input I _{IH} /I _{IL} Output I _{OH} /I _{OL}	
A _n , B _n	Inputs	1.0/2.0	20 μA/-1.2 mA	
\overline{O}_n	Outputs	600/106.6 (80)	–12 mA/64 mA (48 mA)	

Function Table

Inp	Output		
Α	В	Ю	
L	L	Н	
L	Н	Н	
Н	L	Н	
Н	Н	L	

L H = HIGH Voltage Level L = LOW Voltage Level

Absolute Maximum Ratings(Note 1)

-65°C to +150°C Storage Temperature

-55°C to +125°C Ambient Temperature under Bias Junction Temperature under Bias $-55^{\circ}C$ to $+150^{\circ}C$ V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0V Input Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC} 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0° C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

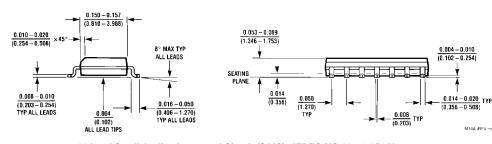
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

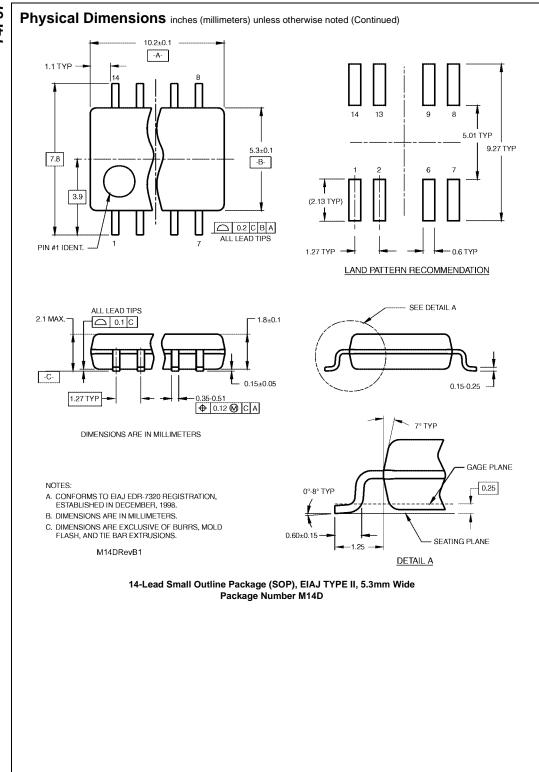
Symbol	Parameter		Min	Тур	Max	Units	v _{cc}	Conditions	
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	$I_{IN} = -18 \text{ mA}$	
V _{OH}	Output HIGH	10% V _{CC}	2.4					$I_{OH} = -3 \text{ mA}$	
	Voltage	10% V _{CC}	2.0			V	Min	$I_{OH} = -15 \text{ mA}$	
		$5\% V_{CC}$	2.7					$I_{OH} = -3 \text{ mA}$	
V _{OL}	Output LOW	10% V _{CC}			0.55	V	Min	I _{OL} = 64 mA	
	Voltage								
I _{IH}	Input HIGH				5.0	μА	Max	$V_{IN} = 2.7V$	
	Current								
I _{BVI}	Input HIGH Current				7.0	μΑ	Max	V _{IN} = 7.0V	
	Breakdown Test								
I _{CEX}	Output HIGH				50	μΑ	Max	V _{OUT} = V _{CC}	
	Leakage Current								
V _{ID}	Input Leakage		4.75			V	0.0	I _{ID} = 1.9 μA	
	Test							All Other Pins Grounded	
I _{OD}	Output Leakage				3.75	μΑ	0.0	V _{IOD} = 150 mV	
	Circuit Current							All Other Pins Grounded	
IL	Input LOW Current				-1.2	mA	Max	$V_{IN} = 0.5V$	
I _{OS}	Output Short-Circuit Current		-100		-225	mA	Max	V _{OUT} = 0V	
I _{CCH}	Power Supply Current			3.7	6.0	mA	Max	V _O = HIGH	
I _{CCL}	Power Supply Current			28.0	33.0	mA	Max	$V_O = LOW$	

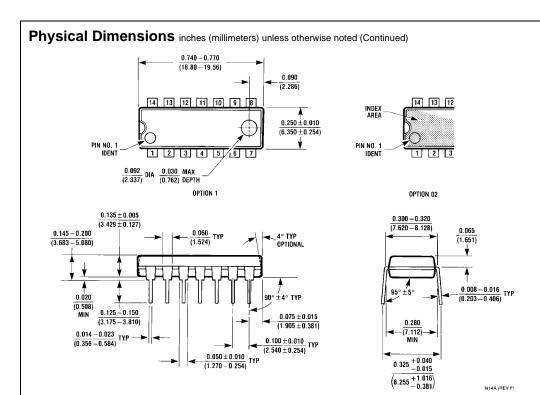
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^{\circ} C$ $V_{CC} = +5.0 V$ $C_L = 50 \ pF$			$T_A = 0$ °C to +70°C $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	
t _{PLH}	Propagation Delay	2.0	3.2	5.5	1.5	6.5	ns
t _{PHL}	A_n , B_n to \overline{O}_n	1.5	2.4	4.5	1.0	5.0	



14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow Package Number M14A





14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N14A

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